



This is the accepted manuscript made available via CHORUS, the article has been published as:

## Orthorhombic BiFeO<sub>3</sub>

J. C. Yang, Q. He, S. J. Suresha, C. Y. Kuo, C. Y. Peng, R. C. Haislmaier, M. A. Motyka, G. Sheng, C. Adamo, H. J. Lin, Z. Hu, L. Chang, L. H. Tjeng, E. Arenholz, N. J. Podraza, M. Bernhagen, R. Uecker, D. G. Schlom, V. Gopalan, L. Q. Chen, C. T. Chen, R. Ramesh, and Y. H. Chu

Phys. Rev. Lett. **109**, 247606 — Published 14 December 2012

DOI: [10.1103/PhysRevLett.109.247606](https://doi.org/10.1103/PhysRevLett.109.247606)

# Orthorhombic BiFeO<sub>3</sub>

J. C. Yang,<sup>1</sup> Q. He,<sup>2,3</sup> S. J. Suresha,<sup>4</sup> C. Y. Kuo,<sup>5,6</sup> C. Y. Peng,<sup>1</sup> R. C. Haislmaier,<sup>7</sup> M. A. Motyka,<sup>8</sup> G. Sheng,<sup>7</sup> C. Adamo,<sup>9</sup> H. J. Lin,<sup>5</sup> Z. Hu,<sup>6</sup> L. Chang,<sup>1</sup> L. H. Tjeng,<sup>6</sup> E. Arenholz,<sup>3</sup> N. J. Podraza,<sup>10</sup> M. Bernhagen,<sup>11</sup> R. Uecker,<sup>11</sup> D. G. Schlom,<sup>9,12</sup> V. Gopalan,<sup>7</sup> L. Q. Chen,<sup>7</sup> C. T. Chen,<sup>5</sup> R. Ramesh,<sup>2</sup> and Y. H. Chu<sup>1,\*</sup>

<sup>1</sup>*Department of Materials Science and Engineering,  
National Chiao Tung University, Hsinchu, 300, Taiwan*

<sup>2</sup>*Department of Physics, University of California, Berkeley, Berkeley, CA 94720, USA*

<sup>3</sup>*Advanced Light Source, Lawrence Berkeley National Laboratory, Berkeley, California 94720, USA*

<sup>4</sup>*National Center for Electron Microscopy, Lawrence Berkeley National Laboratory, Berkeley, CA 94720, USA*

<sup>5</sup>*National Synchrotron Radiation Research Center, Hsinchu 30076, Taiwan*

<sup>6</sup>*Max-Planck Institute for Chemical Physics of Solids,  
Nöthnitzer Straße 40, 01187 Dresden, Germany*

<sup>7</sup>*Department of Materials Science and Engineering,  
Pennsylvania State University, University Park, PA 16802, USA*

<sup>8</sup>*Department of Engineering Science and Mechanics,  
Pennsylvania State University, University Park, PA 16802, USA*

<sup>9</sup>*Department of Materials Science and Engineering, Cornell University, Ithaca, NY 14853, USA*

<sup>10</sup>*Department of Physics and Astronomy, University of Toledo, Toledo, OH 43606, USA*

<sup>11</sup>*Leibniz Institute for Crystal Growth, Max-Born-Straße 2, D-12489 Berlin, Germany*

<sup>12</sup>*Kavli Institute at Cornell for Nanoscale Science, Ithaca, NY 14853, USA*

(Dated: November 9, 2012)

A new orthorhombic phase of the multiferroic BiFeO<sub>3</sub> has been created via strain engineering by growing it on a NdScO<sub>3</sub>(110)<sub>o</sub> substrate. The tensile-strained orthorhombic BiFeO<sub>3</sub> phase is ferroelectric and antiferromagnetic at room temperature. A combination of nonlinear optical second harmonic generation and piezoresponse force microscopy revealed that the ferroelectric polarization in the orthorhombic phase is along the in-plane  $\langle 110 \rangle_{pc}$  directions. In addition, the corresponding rotation of the antiferromagnetic axis in this new phase was observed using X-ray linear dichroism.

Multiferroics possess simultaneous electric and magnetic order parameters and the potential to manipulate one through the other [1]. Motivated by potential applications and fundamental understanding, the single-phase, room-temperature multiferroic BiFeO<sub>3</sub> (BFO), has played a key role in rejuvenating this field [2]- [6]. Recently, a strain driven iso-symmetric phase transition has been demonstrated in this material system [7]. Experimentally, tetragonal, strained rhombohedral, and mixed-phase BFO thin films have been created and widely studied to show enhanced either piezo/ferroelectricity or magnetism. Triggered by this, several theoretical predictions suggest a rich strain-temperature phase diagram composing phases with different symmetries [7], [8]. In this study, we start from phase-field modeling to provide an extended scenario of the BFO phase diagram, specifically under biaxial tensile stress imposed through a lattice mismatched substrate. In conjunction with experimental data we demonstrate the existence of an orthorhombic phase in epitaxial films subjected to such stresses.

We employed the same material constants [9] of BFO and computational approach as described in our previous work [10]. The domain stability of a (001)<sub>pc</sub> BFO thin film under tensile biaxial constraint is calculated via phase-field simulations, and the predicted strain-temperature phase stability diagrams with short-circuit and open-circuit boundary conditions are shown in Figs. 1(a) and 1(b), respectively. In both diagrams,

the stable phases are labeled as cubic paraelectric, distorted rhombohedral (R), orthorhombic (O) and the mixture of R and O phases (R+O). In order to obtain the phase stability and phase boundaries, the spatial distribution of the polarization field is determined by numerically solving the time dependent Ginzburg-Landau (TDGL) equations [11]. We use a background dielectric constant  $\kappa=10$  in the calculation [12]; for the open-circuit diagram in Fig. 1(b), the phase boundary predicted from the vacuum dielectric constant of 1 is also presented for comparison.

As shown in Figs. 1(a) and 1(b), the electric boundary condition has a significant impact on the distorted rhombohedral/orthorhombic phase boundary for BFO thin films. Fig. 1(a) shows that the distorted rhombohedral phase transforms to the orthorhombic phase at  $\sim 1.7\%$  tensile strain at room temperature (300K), and the pure orthorhombic phase cannot be stabilized until the strain magnitude is higher than  $\sim 2.2\%$ . This short-circuit diagram is essentially the same as the tensile part of the previous reported diagram. [7]

The open-circuit boundary condition leads, however, to a dramatically different phase diagram (Fig. 1(b)). The depolarization field suppresses the out-of-plane polarization and promotes the formation of orthorhombic domains, leading to a mixture of distorted rhombohedral and orthorhombic phases even at zero misfit strain. For comparison, we also calculated the phase boundary

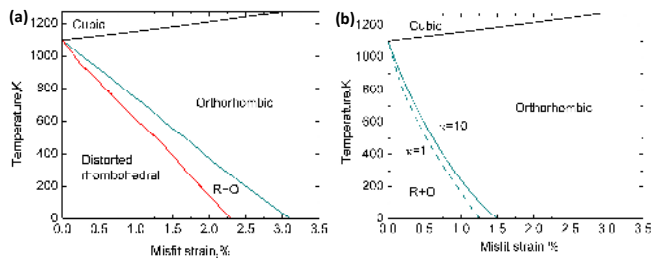


FIG. 1. (color online) Strain-temperature phase diagrams of  $\text{BiFeO}_3$  thin film from phase-field simulations. (a) Under short-circuit boundary condition and (b) under open-circuit boundary conditions.

assuming the dielectric constant of vacuum in the electrostatic equation. The depolarization field effect plays an important role in mediating the phases of BFO thin films under tensile strains. Although we observe a larger depolarization field effect, both results demonstrate that BFO with approximately  $\sim 1.0\%$  tensile strain exhibits an orthorhombic phase at room temperature. We also performed additional phase-field simulations [13] by constructing a thermodynamic potential assuming the distorted rhombohedral to orthorhombic phase boundary at  $8\%$  tensile strain at  $0\text{K}$ , based on a recent density function calculation reported by Dupe' *et al.* [14]. This modified potential leads to a mixture of orthorhombic and distorted rhombohedral phase under the open-circuit boundary condition for BFO with  $1.0\%$  strain.

To assess the validity of the strain phase diagrams in Fig. 1, BFO films were prepared on substrates that impart biaxial strain due to epitaxial mismatch. In this study, we synthesized  $15\text{ nm}$  thick epitaxial BFO thin films on orthorhombic  $\text{NdScO}_3(110)_o$  (NSO, with pseudocubic spacing  $4.01\text{Å}$ ) [15] substrates, which provides  $\sim 1.1\%$  in-plane tensile strain, via pulsed laser deposition (PLD) at  $700\text{ }^\circ\text{C}$  in an oxygen pressure of  $1 \times 10^{-1}$  Torr and cooled in 1 atmosphere of oxygen. Their commensurate nature was confirmed by four-circle x-ray diffraction. X-ray diffraction  $\theta - 2\theta$  scans of all of the samples studied (from  $15^\circ$  to  $100^\circ$  using  $\text{Cu } K_\alpha$  radiation, not shown here) exhibited only peaks attributable to the epitaxial growth of a phase-pure perovskite film.

The quality of BFO films prepared by PLD and its crystal structure were characterized via transmission electron microscopy (TEM) and high-resolution X-ray reciprocal space mapping (RSM). To avoid possible confusion arising from the index transformation, we refer  $[001]_o$ ,  $[1\bar{1}0]_o$  and  $[110]_o$  directions in the orthorhombic system to the  $[100]_{pc}$ ,  $[010]_{pc}$  and  $[001]_{pc}$  directions in the pseudo-cubic system. High angle annular dark field scanning (HAADF) TEM images and the corresponding fast Fourier transforms (FFT) (Fig. 2(a)) obtained from a  $(010)_{pc}$  cross section reveal the high quality of the epitaxial BFO layer. Analysis of the FFT pattern (inset of Fig. 2(a)) with pseudo-cubic indices yields an

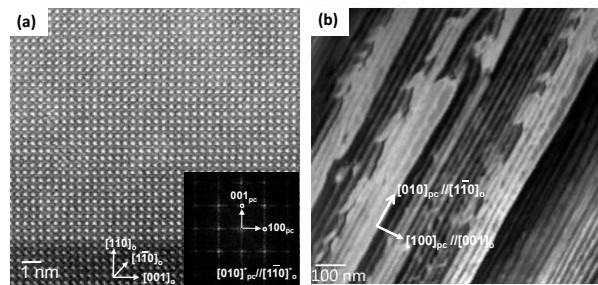


FIG. 2. (color online) TEM micrographs of a  $\text{BiFeO}_3$  thin film on  $\text{NdScO}_3$ . (a) HAADF STEM image of the  $\text{BiFeO}_3/\text{NdScO}_3$  interface of a  $15\text{ nm}$  thick film and corresponding Fourier transforms of the film (inset) indexed with pseudo-cubic indices. (b) Planar view image showing the striped domain pattern in the  $15\text{ nm}$  thick film.

in-plane parameter of  $4.0\text{ Å}$  and an out-of-plane parameter of  $3.90\text{ Å}$ , which results from the tensile constraint exerted by the substrate lattice. This confirms epitaxial growth and a  $0.975\text{ } c/a$  ratio in the tensile strained BFO; the FFT pattern and the suppressed  $c/a$  ratio imply an orthorhombic symmetry. Furthermore, direct observation of the domain boundaries in plan-view TEM images (Fig. 2(b)) reveal stripe-like contrast, reflecting the anisotropic lattice structure in such a tensile strained BFO. For further confirmation, reciprocal space maps (RSM) were obtained from two incident directions with respect to the NSO substrate: one has the incident x-ray parallel to  $[100]_{pc}$  (Fig. 3(a)), and the other is parallel to  $[010]_{pc}$  (Fig. 3(b)). The coordinate axis,  $q_i$ , represents the  $i$ -axis component of the reciprocal space vector. Both symmetric RSM ( $003_{pc}$  reflections) and asymmetric RSMs ( $103_{pc}$  and  $013_{pc}$ ) are measured for depiction of the whole structure. In the  $[100]_{pc}$  incidence, RSM reveals a "dragonfly-like" set comprising four peaks in each map (labeled as 1 to 8). Peaks labeled as 4 and 8 come from the NSO substrate and the peaks of 1,2,3 and 5,6,7 are all ascribed to the BFO film. At first glance, it is intriguing to note the split peaks (labeled as 1,3 and 5,7) of BFO, which usually result from tilted crystal structures or satellite reflections of the periodic domain structures. Detailed  $q_x$ -scan measurements have been employed to reveal the origin of the splitting, (see Supplemental Materials, Fig. S1). These studies show that the length of the splitting remains the same (namely,  $\Delta q_x = 0.006$  for all the  $(00L)$  BFO reflections) irrespective of the reciprocal plane spacing. Comparing both the experimental and simulation results leads us the conclusion that the split peaks are caused by the satellite reflection arising from the periodic domain structures ( $\sim 16\text{ nm}$  average lateral size of the stripe domain). We found that the  $(003)_{pc}$  peaks of BFO are well aligned at  $q_z \sim 0.77\text{ Å}^{-1}$ , and the all spots for BFO and NSO appear at virtually the sample  $q_x$  and  $q_y$  in-plane interplanar spacing. These indicate

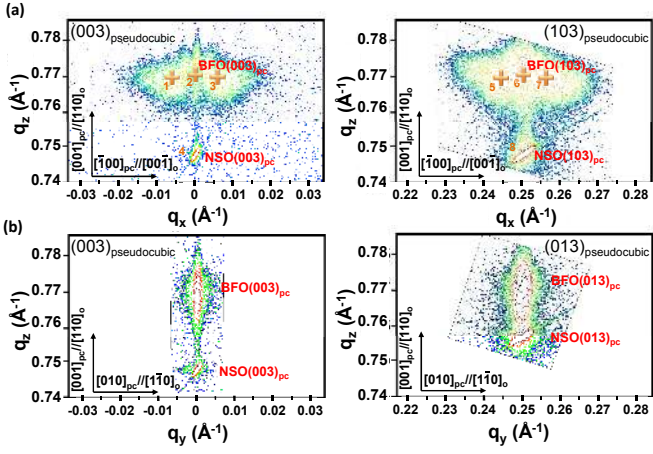


FIG. 3. (color online) X-ray reciprocal space mapping studies of a BiFeO<sub>3</sub> thin film on NdScO<sub>3</sub>. Symmetric and asymmetric reciprocal space maps of BiFeO<sub>3</sub> and NdScO<sub>3</sub> with the incident x-ray beam along (a) [100]<sub>pc</sub> and (b) [010]<sub>pc</sub> directions. Corresponding BiFeO<sub>3</sub> and NdScO<sub>3</sub> main peaks are also labeled with pseudo-cubic indexes.

that both the in-plane interplanar lattice parameters of the BFO film and the NSO substrate are very close to each other. The lattice parameters of this structure are calculated to be  $a \sim 3.99$  Å,  $b \sim 4.00$  Å and  $c \sim 3.89$  Å for BFO. By comparing both symmetrical and asymmetrical RSM results, we conclude that this phase possesses  $\beta=\gamma=90^\circ$  structure, moreover, it shows an offset tilting angle from the [001]<sub>pc</sub> substrate normal by  $\sim 0.63^\circ$  along the [010]<sub>pc</sub> directions.

Having established that BFO grown on NSO substrates shows a distorted orthorhombic structure, we now turn to investigate the correlation of structural symmetry and polarization. Herein, the linear and nonlinear optical properties of the orthorhombic(O) phase BFO thin film are presented. Linear optical properties of BFO with different structures were obtained from room temperature ellipsometric spectra, see Supplemental Material, Fig. S2. A similar approach has been used to interpret the structural strain and local symmetry breaking [16].

To determine the point group symmetry of the BFO/NSO film, nonlinear optical second harmonic generation (SHG) was used, which is a domain symmetry-sensitive technique for polar materials. SHG is a process whereby two photons of frequency  $\omega$  are converted into one photon of frequency  $2\omega$  by a nonlinear medium through the creation of a nonlinear polarization,  $P_i^{2\omega} = d_{ijk} E_j^\omega E_k^\omega$ , where  $d_{ijk}$  is the nonlinear optical tensor, and  $E_{j,k}^\omega$  is the fundamental electric field. While the observation of SHG indicates the existence of a polar phase, the anisotropy of the SHG signal can reveal the point group symmetry of a material [17]. SHG experiments were performed on BFO/NSO thin film with an 800 nm fundamental beam (Ti:sapphire laser, 80 fs pulses, 1 kHz repetition rate). The experimental geometry is shown in Fig. 4(a). Based on the TEM data, we consider an

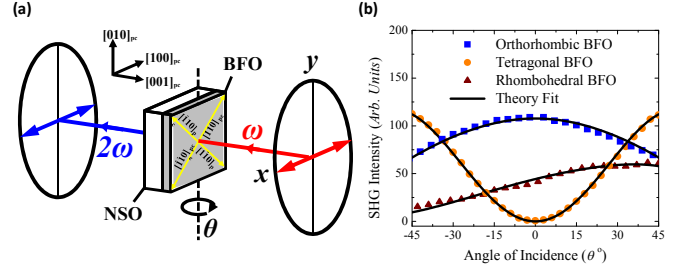


FIG. 4. (color online) Nonlinear optical second harmonic generation of orthorhombic BiFeO<sub>3</sub>. (a) The experimental geometry for SHG tilt scans with the incident electric field and detected SHG both along the  $x$ -direction. The four possible polarization variants are shown as yellow lines on the BFO film surface along the  $\langle 110 \rangle_{pc}$  directions. (b) Tilt scans showing SHG intensity as a function of incidence angle ( $\theta$ ) for orthorhombic (001)<sub>pc</sub> BiFeO<sub>3</sub>/(110)<sub>o</sub> NdScO<sub>3</sub> (blue squares), rhombohedral (111)<sub>pc</sub> BiFeO<sub>3</sub>/(111)<sub>pc</sub> SrTiO<sub>3</sub> (red triangles), and tetragonal (001)<sub>pc</sub> BiFeO<sub>3</sub>/(110)<sub>o</sub> YAlO<sub>3</sub> (orange circles), with the corresponding theory fits shown in black lines.

orthorhombic,  $mm2$  (with  $\{001\}_{pc}$  and  $\{110\}_{pc}$  mirror planes), model structure where we assume the polar direction of the four possible domain variants are along the  $\langle 110 \rangle_{pc}$  directions, shown as yellow arrows on the surface in Fig. 4(a). If the polarization lies in the plane of the film as predicted [14], the SHG signal will have maximum intensity at normal incidence ( $\theta = 0^\circ$ ) since the fundamental electric field will sample the largest polarization component in this configuration. If the sample is rotated about the  $y$ -axis, the SHG signal should decrease symmetrically about normal incidence. Fig. 4(b) shows the SHG intensity (blue squares) detected along the  $x$ -axis, as the sample was rotated between  $\theta = \pm 45^\circ$  about the  $y$ -axis, with the orthorhombic model fit (black line). The mathematical model for the SHG intensity for a thin film on a substrate is shown in detail in Reference [18]. The effective nonlinear optical  $d$  coefficient for orthorhombic  $mm2$  symmetry along  $x$ -direction is given by

$$d_{eff} \propto (\sin 2\theta_\omega \sin \theta_{2\omega} + 2(K_{1,x} \cos^2 \theta_\omega + K_{2,x} \sin^2 \theta_\omega) \cos \theta_{2\omega}) \quad (1)$$

where the  $K_{1,x}$ ,  $K_{2,x}$  terms are functions of the  $d_{ijk}$  tensor coefficients and  $\theta_\omega(\theta_{2\omega})$  are the refractive angles for the fundamental (second harmonic) beams respectively. Also shown in Fig. 4(b) are tilt scans for molecular beam epitaxy (MBE) grown tetragonal BFO/YAlO<sub>3</sub> (orange circles), and rhombohedral BFO/SrTiO<sub>3</sub> (red triangles) thin films, with corresponding theory fits shown as black lines [19]. The generated SHG for tetragonal ( $4mm$ ) point group symmetry (out-of-plane polarization) is zero at normal incidence and symmetric, whereas for rhombohedral ( $3m$ ) point group symmetry, the SHG response is asymmetric, in clear contrast to the SHG tilt scan curve for the orthorhombic BFO.

Piezoresponse force microscopy (PFM) was employed to probe the local ferroelectricity. Using this approach, the in-plane (IP) FE domain structure is manifested by

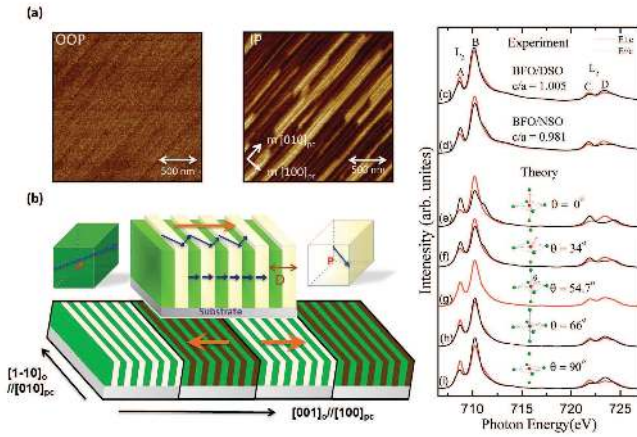


FIG. 5. (color online) PFM and x-ray absorption spectroscopy studies on orthorhombic  $\text{BiFeO}_3$ . (a) OOP-PFM and IP-PFM images obtained under a 5V AC bias on a 15 nm thick  $\text{BiFeO}_3/\text{NdScO}_3$  sample. (b) Schematic of FE domain structures of orthorhombic  $\text{BiFeO}_3$ . The blue arrows depict the ferroelectric polarization directions in each domain, while the orange arrows show the net ferroelectric polarization. Experimental (c)-(d) and theoretical (e)-(i) comparison of polarization dependent Fe- $L_{2,3}$  spectra of  $\text{BiFeO}_3/\text{DyScO}_3$  and  $\text{BiFeO}_3/\text{NdScO}_3$  thin films. The red and black curves correspond to the polarization of x-ray parallel to IP and OOP directions, respectively.

three contrasts, i.e., dark, bright and intermediate, which represent the FE components with IP polarizations toward to the left, right and along the axis of the cantilever, respectively. As for the out-of-plane (OOP) PFM images, the dark and bright contrasts represent the upward and downward polarizations. The PFM results are summarized in Fig. 5(a). First we noticed that the OOP image shows negligible contrast, which is attributed from the crosstalk from IP measurements. The BFO thin film exhibits periodic stripe-like structures (along the  $[010]_{pc}$  direction) in IP measurements. Such results indicate that the  $\langle 111 \rangle_{pc}$  polarization directions in bulk are drastically suppressed in the  $\langle 001 \rangle_{pc}$  directions by the tensile strain. Careful examination of repeating the measurements with sample rotation of  $90^\circ$  and  $180^\circ$  have revealed the  $\langle 110 \rangle_{pc}$  IP polarizations and again confirmed the insignificant contrast in OOP-PFM and the strong contrast in the IP-PFM. As a result, we conclude that the polarizations lie along  $\langle 110 \rangle_{pc}$  directions, which is consistent with our SHG results. In order to minimize the free energy, the most stable configuration of the polarization directions in domain structures are head-to-tail; this suggests that the domain walls should form along  $\langle 010 \rangle_{pc}$ , which is consistent with our PFM and TEM observations, as schematically illustrated in Fig. 5(b).

In order to interrogate both ferroelectric and antiferromagnetic (AFM) order parameters in the orthorhombic

BFO phase, we employed linearly polarized soft x-ray absorption spectroscopy (XAS) and x-ray linear dichroism (XLD). XLD is the difference of the absorption of linearly polarized light, measured at a particular photon energy (e.g., corresponding to the  $\text{Fe}^{3+}$  absorption edge), with orthogonal light polarizations [20]- [25]. BFO thin films possess high spin  $\text{Fe}^{3+}$  ion with a  $2p^63d^5$  ground state; the polarization dependence with respect to magnetization axis shows up as variations in the peak intensities, and the crystal field dichroism also gives to the shifts in the peak positions. In addition to the orthorhombic BFO/NSO sample, a BFO/ $\text{DyScO}_3$  (DSO) sample was used as the reference sample. Owing to the fact that lattice constants of BFO and DSO are very close; therefore, BFO films grown on DSO substrates are almost strain-free as the "parent rhombohedral BFO phase". Figs. 5(c)-(i) show the XAS spectra of the Fe  $L_{2,3}$  edge and their dependence on the direction of the polarization of the x-ray (along the  $a$ -axis (red line) or along the  $c$ -axis (black line)). The XAS peaks resulting from the  $L_3$  edge are marked as A and B, and those resulting from the  $L_2$  edge are marked as C and D.

We first discuss the XAS spectra of the BFO/DSO sample. When comparing the intensities of the XAS peaks at different polarization of x-ray, it is found the intensities of A and C increase when the polarization of x-ray is parallel to the  $a$ -axis of the BFO thin film. B and D, however, show higher intensity when the polarization of x-ray is parallel to the  $c$ -axis. Interestingly, when conducting the same measurements on the BFO/NSO sample, completely opposite results were obtained: the intensities of A and C decrease when the polarization of x-ray is parallel to the  $a$ -axis of the BFO thin film, and the intensities of B and D are lower when the polarization of x-ray is parallel to the  $c$ -axis. This finding suggests that a rotation of the AFM-axis occurs when subjected to different strain states [20], [21].

To extract the orientations of these AFM-axes, we have simulated the experimental spectra using configuration interaction cluster calculations, based on atomic multiplet theory and the local effects of the solid [26], [27]. It takes into account of the intra-atomic  $3d-3d$  and  $2p-3d$  Coulomb interactions, the atomic  $2p$  and  $3d$  spin orbit couplings, the oxygen  $2p-3d$  hybridization and local crystal field interactions [28]. The simulations were carried out using the program XTLS 8.3 [26], and the parameters used are listed in Ref. [29]. Figs. 5(c)-(i) show a comparison between the experimental Figs. 5(c)-(d) and the simulated Figs. 5(e)-(i) Fe- $L_{2,3}$   $E \perp c$  (red line) and  $E \parallel c$  (black line) XAS spectra of BFO thin films as a function of the angle  $\theta$  between the AFM-axis and the  $c$ -axis. From Figs. 5(e)-(i), the angle  $\theta$  is varied from  $0^\circ$  to  $90^\circ$ , i.e. rotating the magnetic moment from out-of-plane to in-plane. We found that the best agreement between theoretical and experimental spectra occurs at  $\theta=34^\circ$  for BFO/NSO ( $\theta=66^\circ$  for BFO/DSO) and -75 meV splitting

for the  $e_g$  orbitals, reflecting a compressed distortion of  $\text{FeO}_6$  octahedron under a tensile-strain.

In summary, through a combination of theoretical and experimental methods, we demonstrate a pathway to create and stabilize a new orthorhombic phase in multiferroic BFO thin films via strain engineering. Combined with SHG and PFM results, in-plane FE polarization is revealed in the BFO/NSO system at room temperature. XLD measurements have further discovered the rotations of the AFM axis toward to the out-of-plane directions in the orthorhombic structure. This study reveals that the crystal structure has a strong influence on both ferroelectric and antiferromagnetic ordering, but also suggests the possibility of manipulating antiferromagnetic ordering with epitaxial strain in BFO system. Such an approach has opened a new scenario for us to create and manipulate a new polymorph of BFO including its altered interplay between order parameters.

We thank the financial support by the National Science Council, R.O.C. (NSC-101-2119-M-009-003-MY2), Ministry of Education (MOE-ATU 101W961), and Center for interdisciplinary science of National Chiao Tung University. The work at Berkeley is supported by the Director, Office of Science, Office of Basic Energy Sciences, Materials Sciences Division of the US department of Energy under contract No. DE-AC02-05CH1123. Gopalan acknowledges support for the national science foundation, DMR-0820404 and DMR-1210588. The work at Penn State is supported by DOE Basic Sciences under Grant No. DOE DE-FG02-07ER46417 (Sheng and L. Q. Chen). The work at Cornell is supported by Army Research Office (ARO) grant W911NF-08-2-0032.

---

\* Corresponding author: yhc@cc.nctu.edu.tw

- [1] R. Ramesh and N.A. Spaldin, *Nature Mater.* **6** 21 (2007).
- [2] J. Wang, J. B. Neaton, H. Zheng, V. Nagarajan, S. B. Ogale, B. Liu, D. Viehland, V. Vaithyanathan, D. G. Schlom, U. V. Waghmare, N. A. Spaldin, K. M. Rabe, M. Wuttig and R. Ramesh, *Science* **299** 1719 (2003).
- [3] J. Wang, H. Zheng, Z. Ma, S. Prasertchoung, M. Wuttig, R. Droopad, J. Yu, K. Eisenbeiser and R. Ramesh, *Appl. Phys. Lett.* **85** 2574 (2004).
- [4] F. Zavaliche, P. Shafer, R. Ramesh, M. P. Cruz, R. R. Das, D. M. Kim, and C. B. Eom, *Appl. Phys. Lett.* **87** 252902 (2005).
- [5] S. Y. Yang, F. Zavaliche, L. Mohaddes-Ardabili, V. Vaithyanathan, D. G. Schlom, Y. J. Lee, Y. H. Chu, M. P. Cru, Q. Zhan, T. Zhao, and R. Ramesh, *Appl. Phys. Lett.* **87** 102903 (2005).
- [6] R. R. Das, D. M. Kim, S. H. Baek, C. B. Eom, F. Zavaliche, S. Y. Yang, R. Ramesh, Y. B. Chen, X. Q. Pan, X. Ke, M. S. Rzechowski, and S. K. Streiffer, *Appl. Phys. Lett.* **88** 242904 (2006).
- [7] R. J. Zeches, M. D. Rossell, J. X. Zhang, A. J. Hatt, Q. He, C. H. Yang, A. Kumar, C. H. Wang, A. Melville, C. Adamo, G. Sheng, Y. H. Chu, J. F. Ihlefeld, R. Erni, C. Ederer, V. Gopalan, L. Q. Chen, D. G. Schlom, N. A. Spaldin, L. W. Martin, and R. Ramesh, *Science* **326**, 977 (2009).
- [8] I. C. Infante, S. Lisenkov, B. Dupe', M. Bibes, S. Fusil, E. Jacquet, G. Geneste, S. Petit, A. Courtial, J. Juraszek, L. Bellaiche, A. Barthelemy and B. Dkhil, *Phys. Rev. Lett.* **105**, 057601 (2010).
- [9] J. X. Zhang, D. G. Schlom, L. Q. Chen, and C. B. Eom, *Appl. Phys. Lett.* **95**, 122904 (2009).
- [10] J. X. Zhang, Y. L. Li, S. Choudhury, L. Q. Chen, Y. H. Chu, F. Zavaliche, M. P. Cruz, R. Ramesh, and Q. X. Jia, *J. Appl. Phys.* **103**, 094111(2008).
- [11] L. Q. Chen, *Annu. Rev. Mater. Res.* **32**, 113 (2002).
- [12] A. K. Tagantsev, *Ferroelectrics* **375**, 19 (2008).
- [13] G. Sheng and L. Q. Chen, unpublished, 2012.
- [14] B. Dupe', S. Prosandeev, G. Geneste, B. Dkhil, and L. Bellaiche, *Phys. Rev. Lett.* **106**, 237601 (2011).
- [15] B. Veličkov, V. Kahlenberg, R. Bertram, and M. Bernhagen, *Z. Kristallogr* **222**, 466 (2007).
- [16] P. Chen, N. J. Podraza, X. S. Xu, A. Melville, E. Vlachos, V. Gopalan, R. Ramesh, D. G. Schlom, and J. L. Musfeldt, *Appl. Phys. Lett.* **96**, 131907 (2010).
- [17] S. A. Denev, T. T. A. Lummen, E. Barnes, A. Kumar, V. Gopalan, *J. Am. Ceram. Soc.* **94**, 2699 (2011).
- [18] W. N. Herman, L. M. Hayden, *J. Opt. Soc. Am. B* **12**, 416 (1995).
- [19] Y. Cong, I. An, K. Vedam, and R. W. Collins, *Appl. Opt.* **30**, 2692 (1991).
- [20] P. Kuiper, B. G. Searle, P. Rudolf, L. H. Tjeng and C. T. Chen, *Phys. Rev. Lett.* **70** 1549(1993).
- [21] A. Scholl, J. Stohr, J. Luning, J. W. Seo, J. Fompeyrine, H. Siegwart, J. P. Locquet, F. Nolting, S. Anders, E. E. Fullerton, M. R. Scheinfein, and H. A. Padmore, *Science* **287** 1014 (2000).
- [22] F. Nolting, A. Scholl, J. Stohr, J. W. Seo, J. Fompeyrine, H. Siegwart, J. P. Locquet, S. Anders, J. Luning, E. E. Fullerton, M. F. Toney, M. R. Scheinfein and H. A. Padmore, *Nature* **405** 767 (2000).
- [23] S. I. Csiszar, M. W. Haverkort, Z. Hu, A. Tanaka, H. H. Hsieh, H. J. Lin, C. T. Chen, T. Hibma, and L. H. Tjeng, *Phys. Rev. Lett.* **95** 187205 (2005).
- [24] E. Arenholz, G. vanderLaan, R. V. Chopdekar and Y. Suzuki, *Phys. Rev. B* **74** 094407 (2006).
- [25] N. Hollmann, Z. Hu, T. Willers, L. Bohaty, P. Becker, A. Tanaka, H. H. Hsieh, H. J. Lin, C. T. Chen, and L. H. Tjeng, *Phys. Rev. B* **82** 184429 (2010).
- [26] F. M. F. de Groot, *J. Electron Spectrosc. Relat. Phenom.* **67** 529 (1994).
- [27] A. Tanaka and T. Jo, *J. Phys. Soc. Jpn.* **63** 2788 (1994).
- [28] A. E. Bocquet, T. Mizokawa, K. Morikawa, A. Fujimori, S. R. Barman, K. Maiti, D. D. Sarma, Y. Tokura, and M. Onoda, *Phys. Rev. B* **53** 1161 (1996).
- [29]  $\text{FeO}_6$  cluster parameters for all samples:  $\Delta = 2.0\text{eV}$ ,  $U_{dd} = 5.0\text{eV}$ ,  $U_{pd} = 6.0\text{eV}$ , Slater integrals reduced to 70% of Hartree-Fock values. Hex = 63 meV